



## **Integration of pre-fabricated ultra-high density (1000 nF/mm<sup>2</sup>) capacitor films (50-75 microns) onto wafers and panels**

***Himani Sharma, P. M. Raj\* (Presenting author), Parthasarathi Chakraborti, Teng Sun, Nathan Neuhart, Kamil-Paul Rataj^, Saumya Gandhi+, Udo Merker&, Frank Stepniak+, Matt Romig+, Mitch Weaver, Naomi Lollis#, and Rao R. Tummala***

***3D Systems Packaging Research Center, Georgia Institute of Technology, Atlanta, USA***

***^ - H.C.Starck GmbH, Im Schleeke 78-91, 38642 Goslar/Germany***

***+ - Texas Instruments, 13020 TI Blvd, Dallas, TX 75243***

***# A.V.X. Corporation, One AVX Blvd, Fountain Inn, SC 29644***

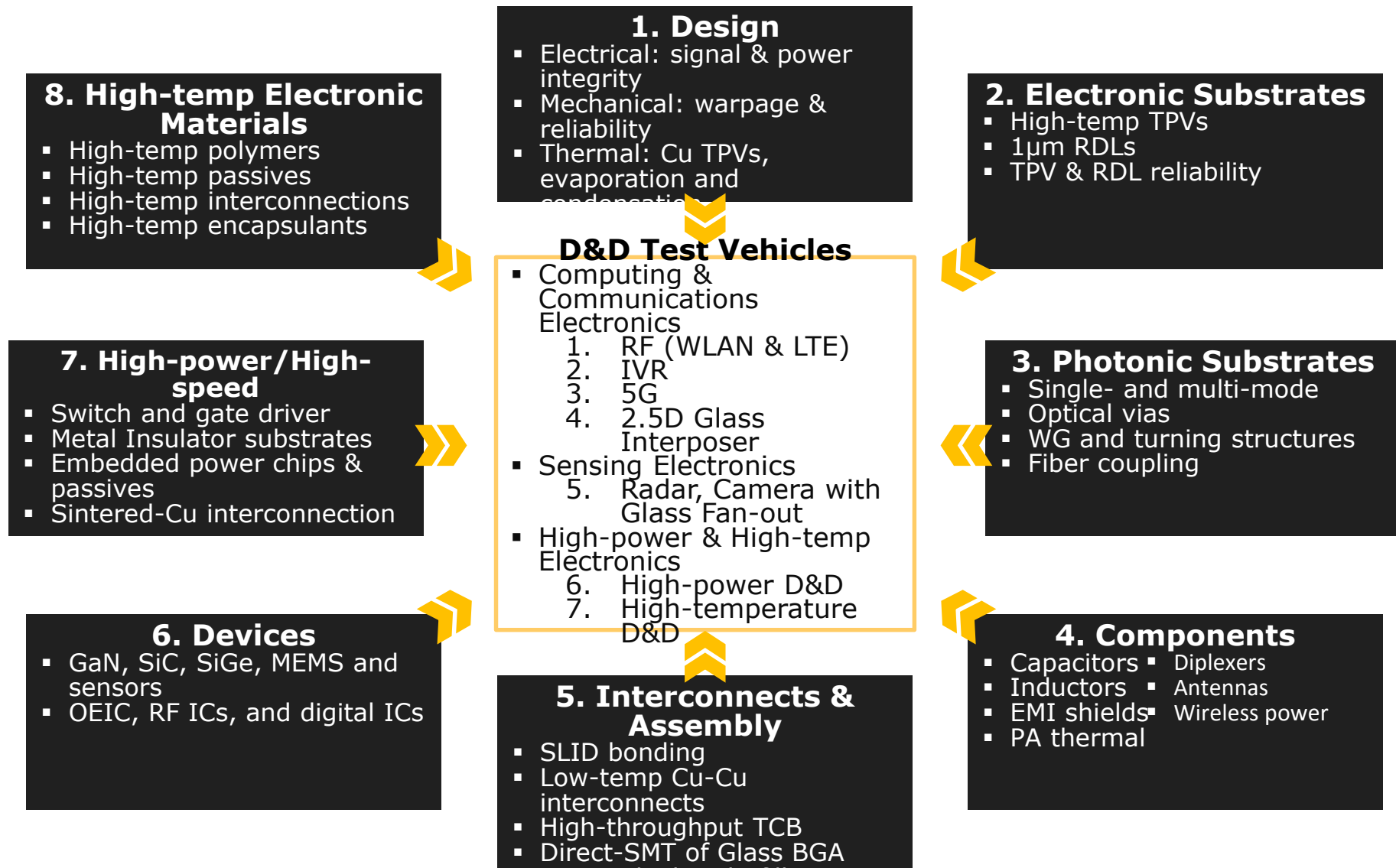
***& Heraeus Inc., Leverkusen, Germany.***

---

# Outline

- Introduction to GT Packaging Research Center
- Capacitor needs for consumer, telecom and automotive industry
- Capacitor integration strategies
- Tantalum film capacitors on silicon
  - Capacitor Integration
  - Capacitor performance
  - Reliability studies
- Integrated voltage regulator (IVR) with capacitors and inductors

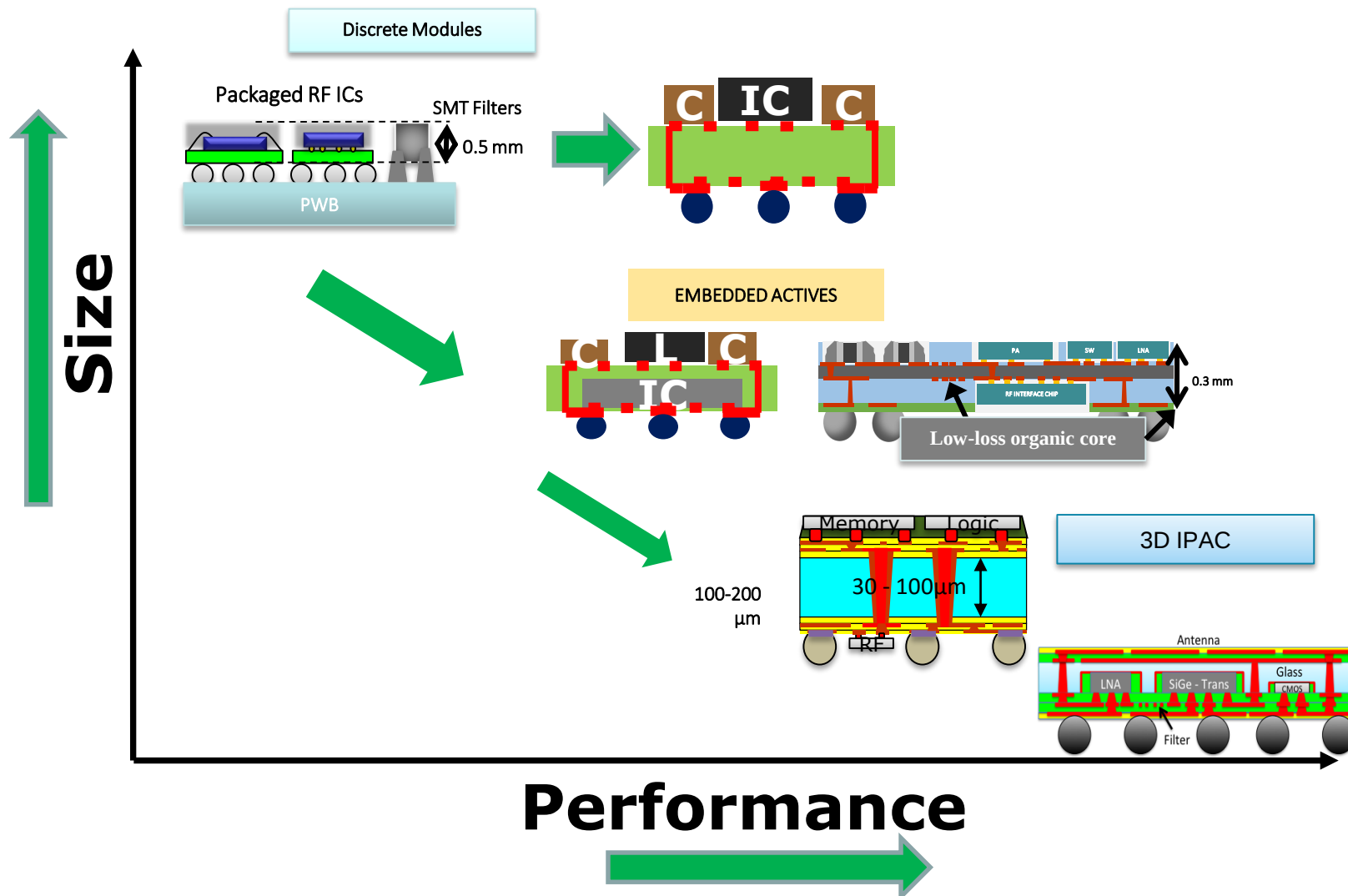
# Packaging Research at Georgia Tech



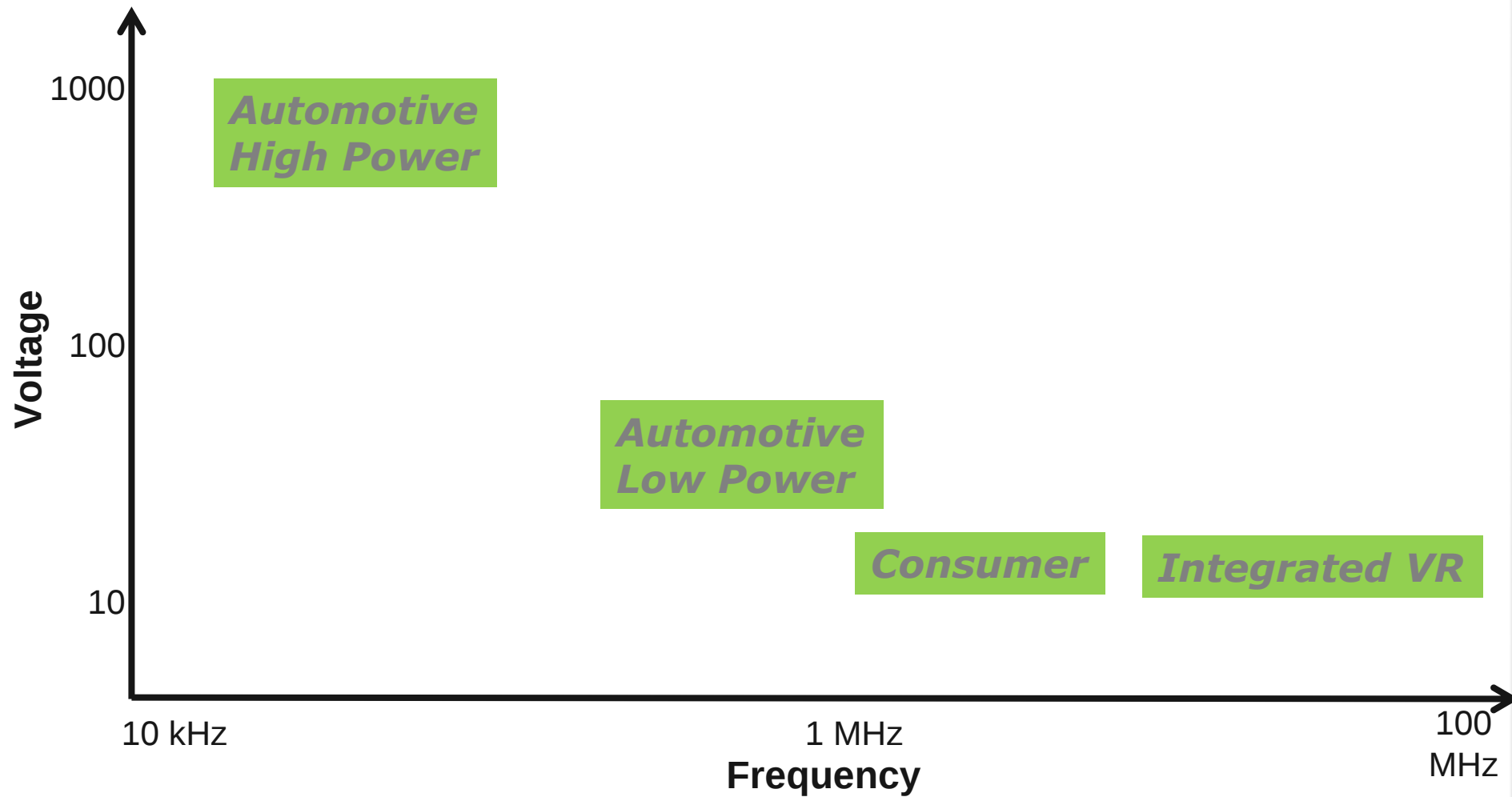
# Why Collaborate With Georgia Tech PRC

- No. 1 Academic Leader in IC & Systems Packaging
- Technical Vision Consistent with Market Needs
- Co-development of Panel-based Glass Packaging with 50 Global Researchers, Developers, Manufacturers and users
- Explore and Develop Advanced Systems Packaging Technologies Beyond Industry's 3-year Horizon
- Seamless from R&D, Prototype, and Tech Transfer Enabling Commercialization
- Track Record of Technology Breakthroughs
- Only 300mm Cleanroom Panel Facility in the Academic World
- > 50 Person Co-development Team: Full-time Researchers, Manufacturing Industry Partners, Graduate Engineers, Faculty and On-campus Industry Engineers
- Leverage: \$8M/100k

# Ultra-miniaturized Power and RF modules with Passive-Active Integration



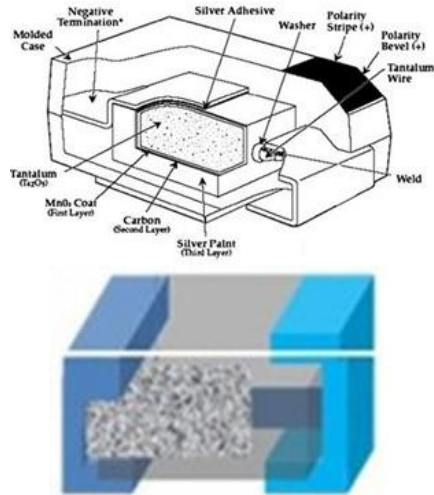
# Capacitor Needs



# Capacitor Technologies

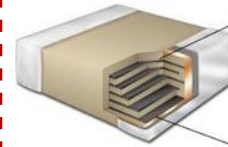
CONFIDENTIAL

## Tantalum

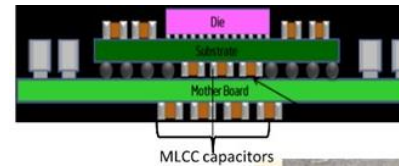


|                     |                                     |
|---------------------|-------------------------------------|
| Cap. Density        | 3 $\mu\text{F}/\text{mm}^2$         |
| Thickness           | 200-800 $\mu\text{m}$               |
| Operating Frequency | 100 Hz – 0.3 MHz                    |
| Leakage current     | $\sim 0.01 \mu\text{A}/\mu\text{F}$ |
| Packaging           | SMD                                 |

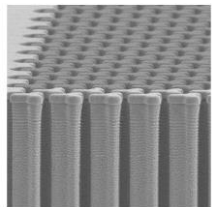
## MLCC



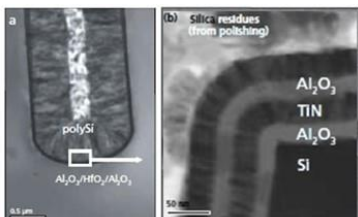
|                     |                                     |
|---------------------|-------------------------------------|
| Cap. Density        | 1 $\mu\text{F}/\text{mm}^2$         |
| Thickness           | 50-800 $\mu\text{m}$                |
| Operating Frequency | 100 Hz – 1 MHz                      |
| Leakage current     | $\sim 0.01 \mu\text{A}/\mu\text{F}$ |
| Packaging           | SMD, thin-film                      |



## Si Trench

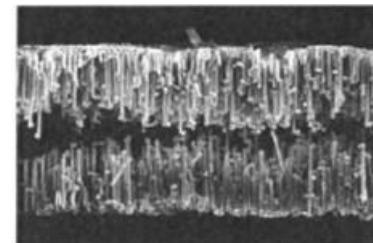


iPDIA



|                     |                                    |
|---------------------|------------------------------------|
| Cap. Density        | $> 0.5 \mu\text{F}/\text{mm}^2$    |
| Thickness           | 100 $\mu\text{m}$                  |
| Operating Frequency | 100 Hz – 1 MHz                     |
| Leakage current     | $\sim 0.1 \mu\text{A}/\mu\text{F}$ |
| Packaging           | thin-film                          |

## Etched Al



|                     |                                     |
|---------------------|-------------------------------------|
| Cap. Density        | 1 $\mu\text{F}/\text{mm}^2$         |
| Thickness           | $\sim 1000 \mu\text{m}$             |
| Operating Frequency | 100 Hz – 0.3 MHz                    |
| Leakage current     | $\sim 0.01 \mu\text{A}/\mu\text{F}$ |
| Packaging           | SMD                                 |

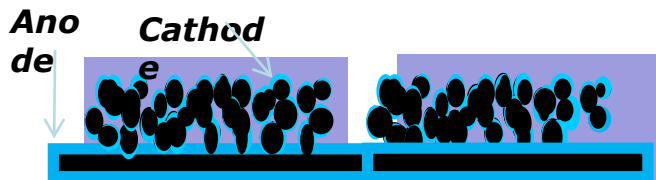
Helsinki

# Silicon-Integrated High-Density Capacitors

CONFIDENTIAL

Component Manufacturer (Ex. AVX)

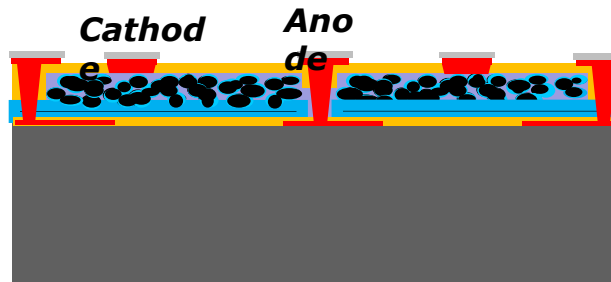
Ta foil



TI  
Wafer



Use standard infrastructure with  
"next-generation" standard  
materials



# Silicon-Integrated High-Density Inductors

Component Manufacturer (Ex. TDK)

High Thermal conductivity dielectric



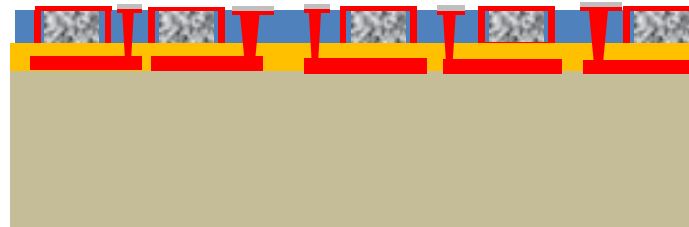
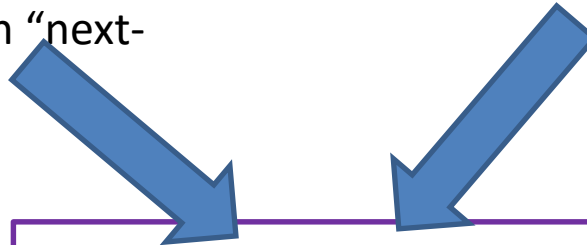
Prepattern magnetic core



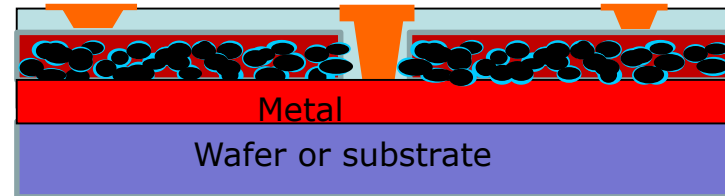
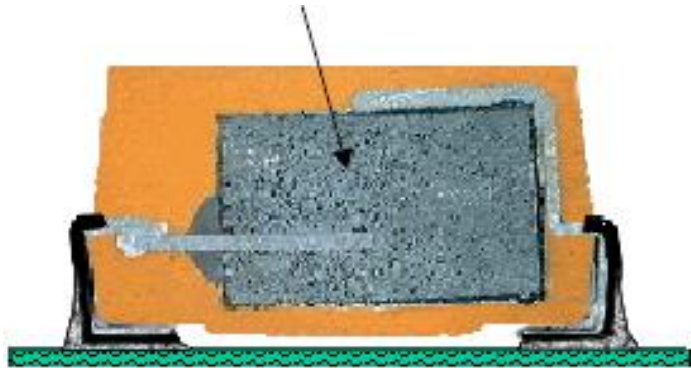
TI Wafer



Use standard infrastructure with “next-generation” standard materials

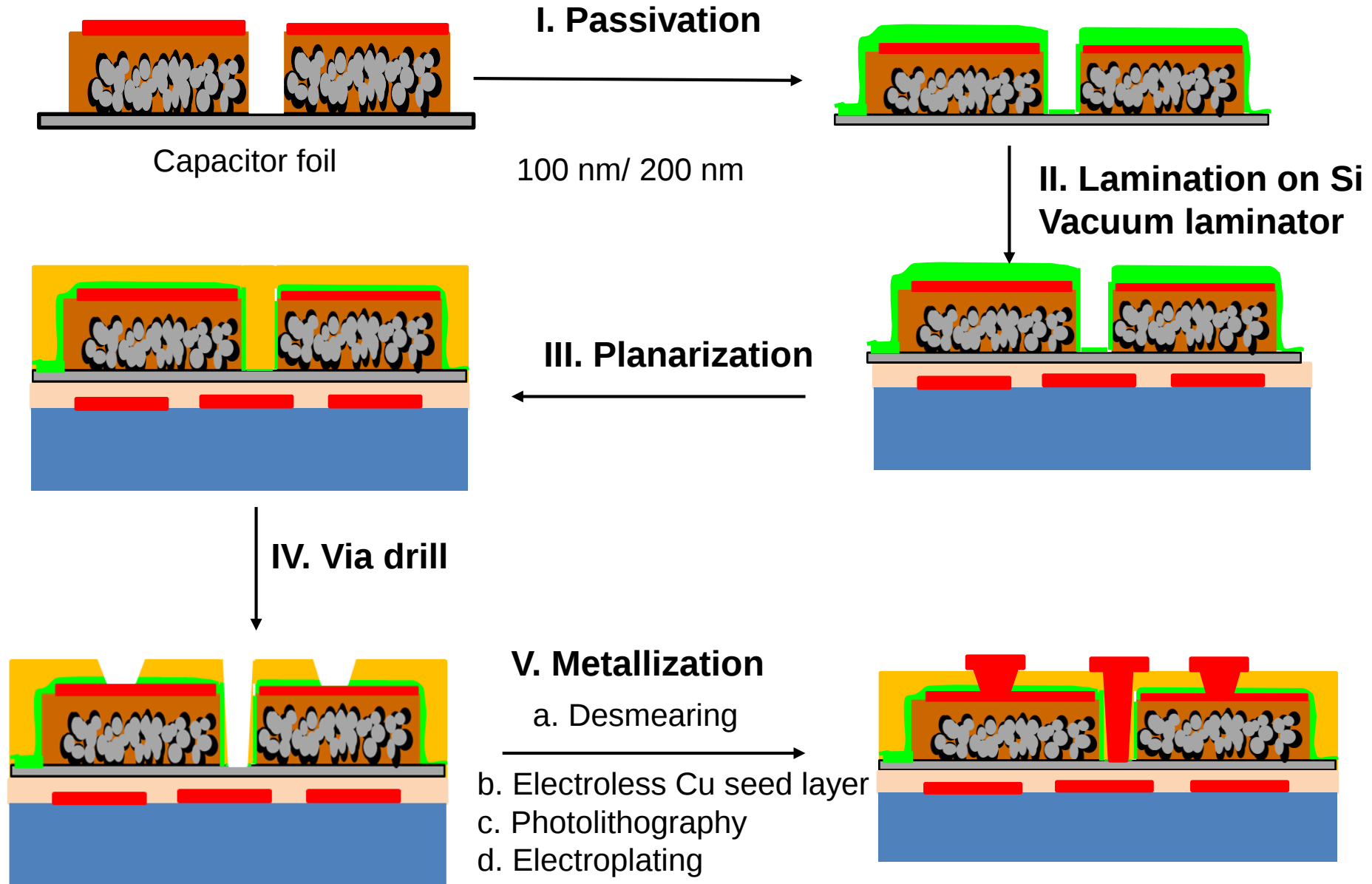


# Bulky Ta Vs Silicon-Integrated Ta Film Capacitors



|                                   |                                                              |
|-----------------------------------|--------------------------------------------------------------|
|                                   |                                                              |
| 200 micron conducting path        | 50 micron conducting path                                    |
| CP/Carbon/Silver paste/lead frame | Minimal interfaces;<br>Direct metallization of CP with Cu/Au |
| 100 milliohms x microfarad        | 20-50 milliohms x microfarad                                 |
| 1-5 MHz                           | >10 MHz                                                      |

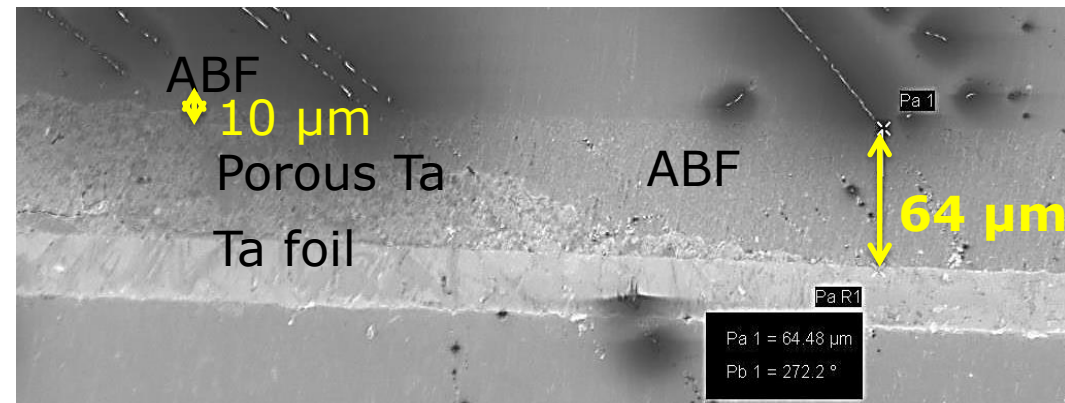
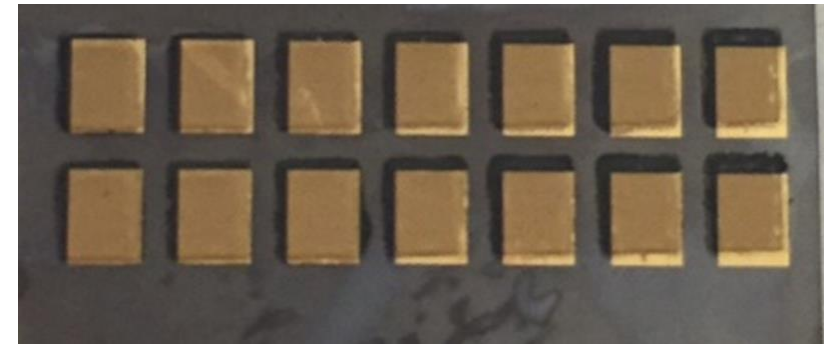
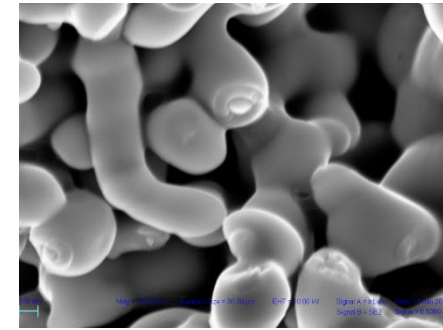
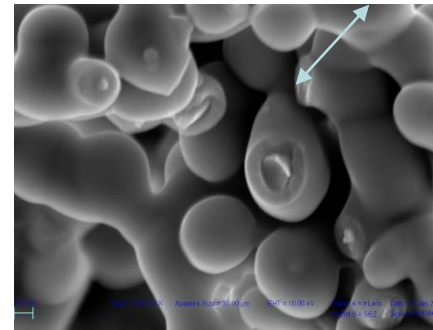
# Capacitor Integration scheme



# Demo. of Capacitor Integration

CONFIDENTIAL

- Sintered tantalum electrodes on tantalum films
- Laminated onto Silicon
- Via connections with laser drilling, metallization



- Anodization voltage- 200V

# Supply Chain Involvement

Component Manufacturer (Ex. AVX)

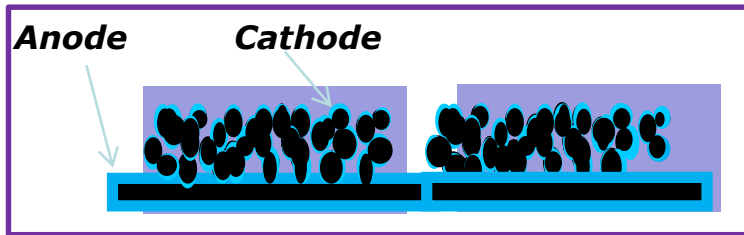
Ta foil



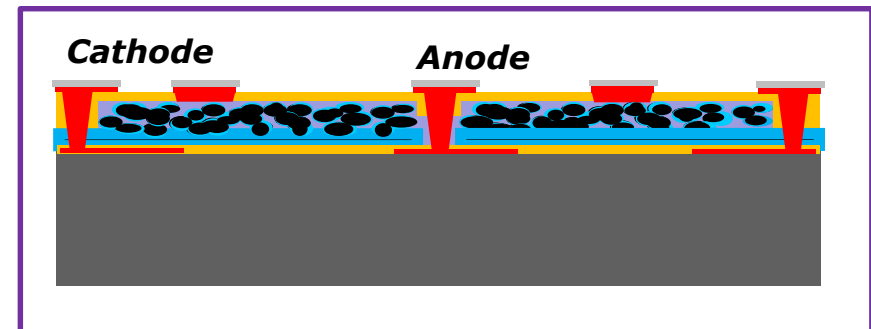
H.C. Starck 

Heraeus

Power modules with passive-active integration

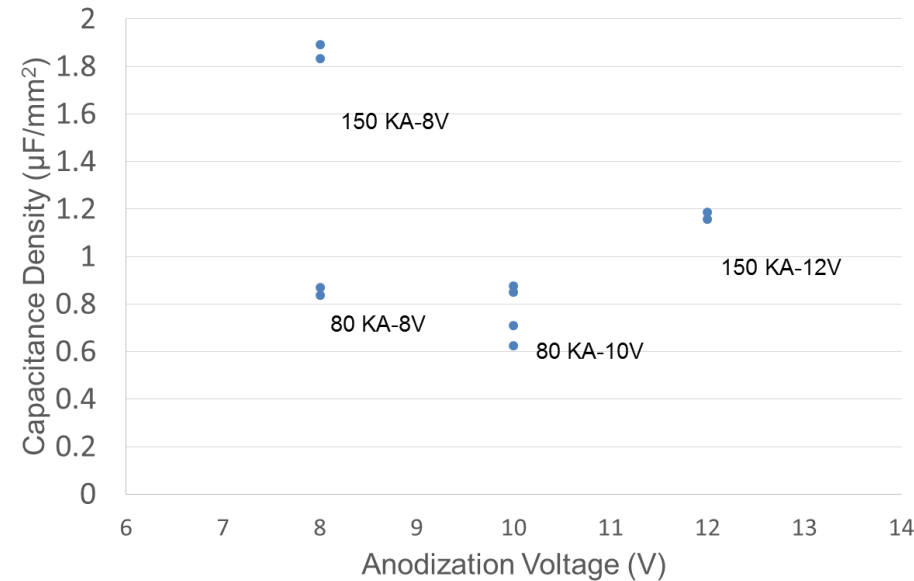
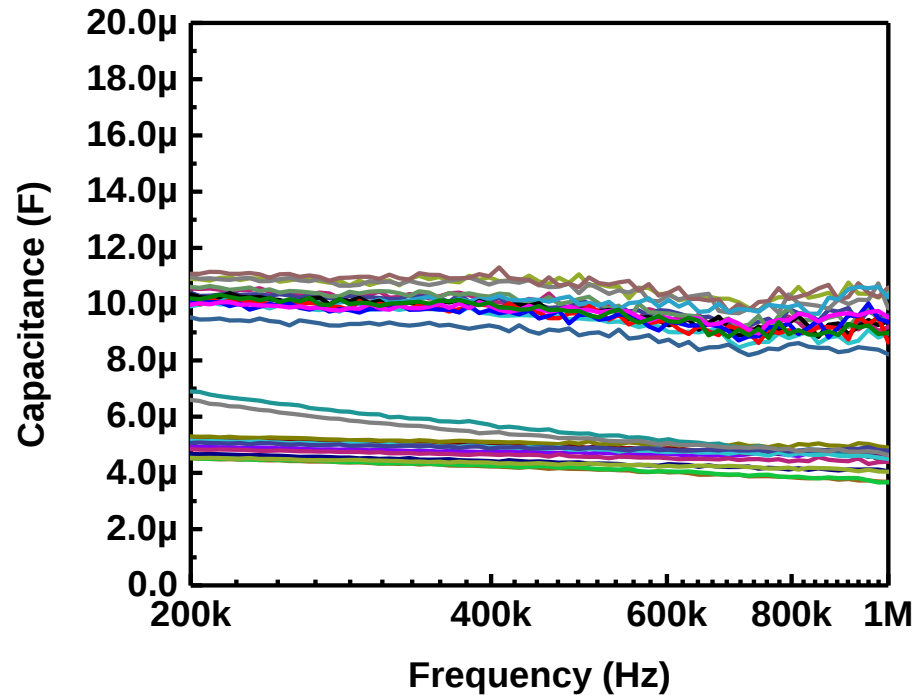


**AVX**



Wafer or substrate

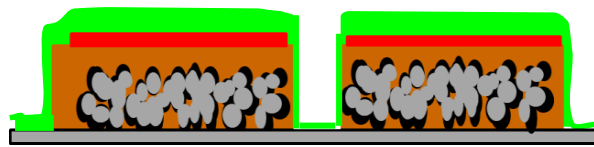
# Capacitor Performance



~ $1\mu\text{F}/\text{mm}^2$  obtained with:

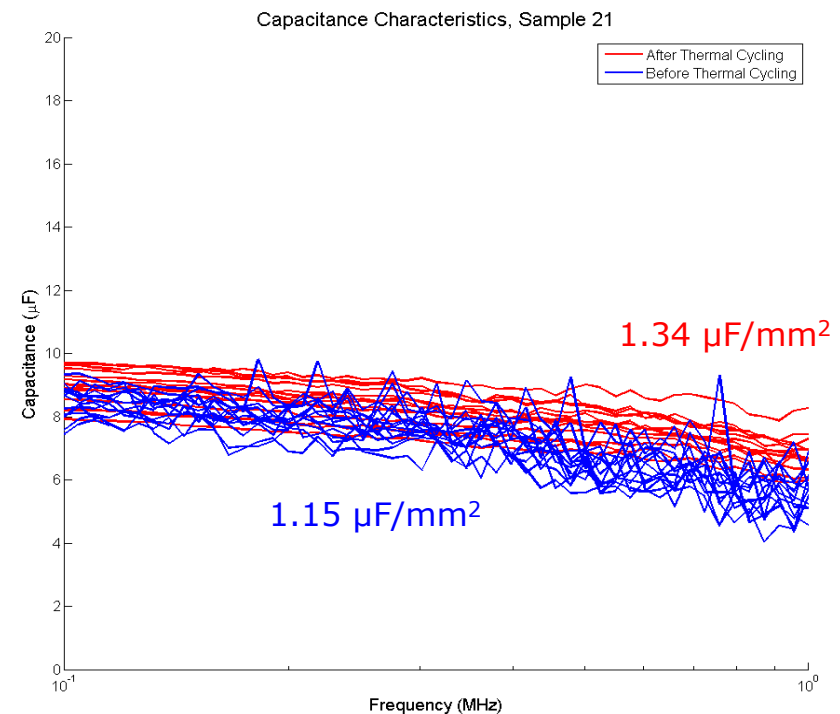
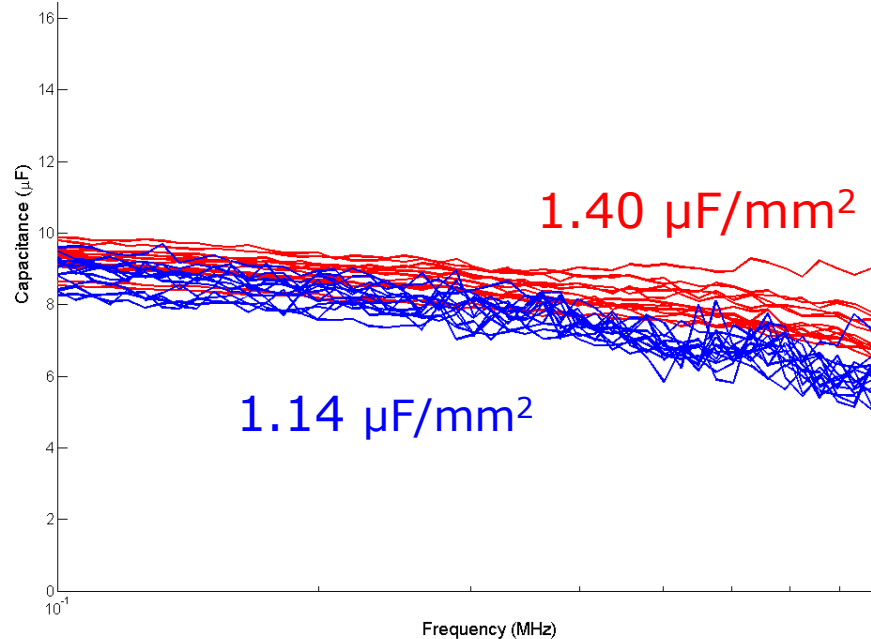
- 80 KA grade with thin dielectric thickness (8V/10V)
- 150 KA with thick dielectric thickness (12V)

# Reliability of passivated capacitors



TCT conditions  $65^{\circ}\text{C}/95\% \text{ RH}, 500 \text{ hrs}$

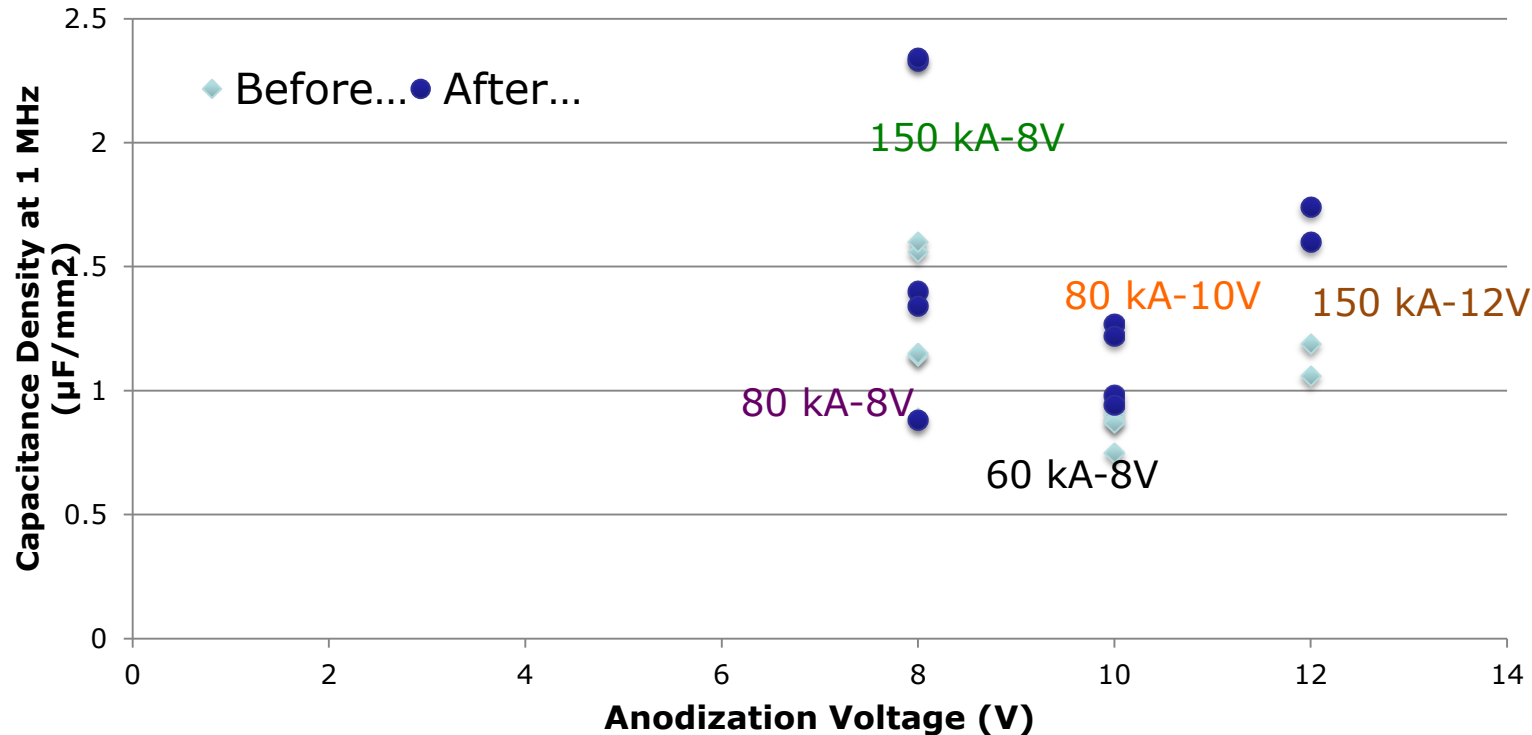
Parlyene thickness- 200 nm



- Increase in capacitance observed post 500 hr of thermal cycling

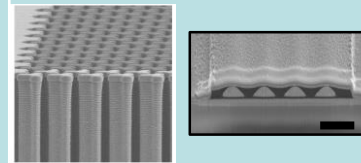
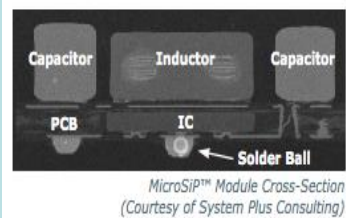
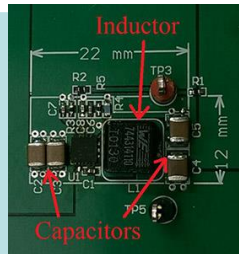
# Reliability of Passivated Capacitors

65°C/95%RH 500 hours



- All foils passed 65/95 for 500 hours
- Capacitance comparable or higher after thermal and moisture test

# Competitiveness of GT Approach with Embedding Si Integrated Ta Capacitors



|                 |                                                             |                                                                    |                                                                      |                                                                       |
|-----------------|-------------------------------------------------------------|--------------------------------------------------------------------|----------------------------------------------------------------------|-----------------------------------------------------------------------|
|                 | <ul style="list-style-type: none"> <li>Discretes</li> </ul> | <ul style="list-style-type: none"> <li>Embedded ICs</li> </ul>     | <ul style="list-style-type: none"> <li>on-chip</li> </ul>            | <ul style="list-style-type: none"> <li>3D Packages</li> </ul>         |
| Inductors       | <ul style="list-style-type: none"> <li>Ferrites;</li> </ul> | <ul style="list-style-type: none"> <li>Embedded or SMDs</li> </ul> | <ul style="list-style-type: none"> <li>Thinfilm inductors</li> </ul> | <ul style="list-style-type: none"> <li>Thinfilm inductors</li> </ul>  |
| Capacitors      | <ul style="list-style-type: none"> <li>MLCCs</li> </ul>     | <ul style="list-style-type: none"> <li>MLCCs</li> </ul>            | <ul style="list-style-type: none"> <li>Trench capacitors</li> </ul>  | <ul style="list-style-type: none"> <li>Thinfilm capacitors</li> </ul> |
| EFFICIENCY      |                                                             |                                                                    |                                                                      |                                                                       |
| POWER HANDLING  |                                                             |                                                                    |                                                                      |                                                                       |
| SIZE            |                                                             |                                                                    |                                                                      |                                                                       |
| COST            |                                                             |                                                                    |                                                                      |                                                                       |
| MANUF READINESS |                                                             |                                                                    |                                                                      |                                                                       |

# Summary

Pioneered a breakthrough capacitor integration technology on wafers and packages:

- Unlimited capacitance density on Silicon
- Low cost – cheaper than traditional discrete passives
- Extensible to high voltages
- Extensible to high frequencies

Created an ecosystem of supply chain involving:

- Material suppliers,
- Component manufacturers
- End-users

Extending this baseline technology to:

- High-voltage power modules: Ex. Automotive
- Automotive battery chargers
- Integrated voltage regulators